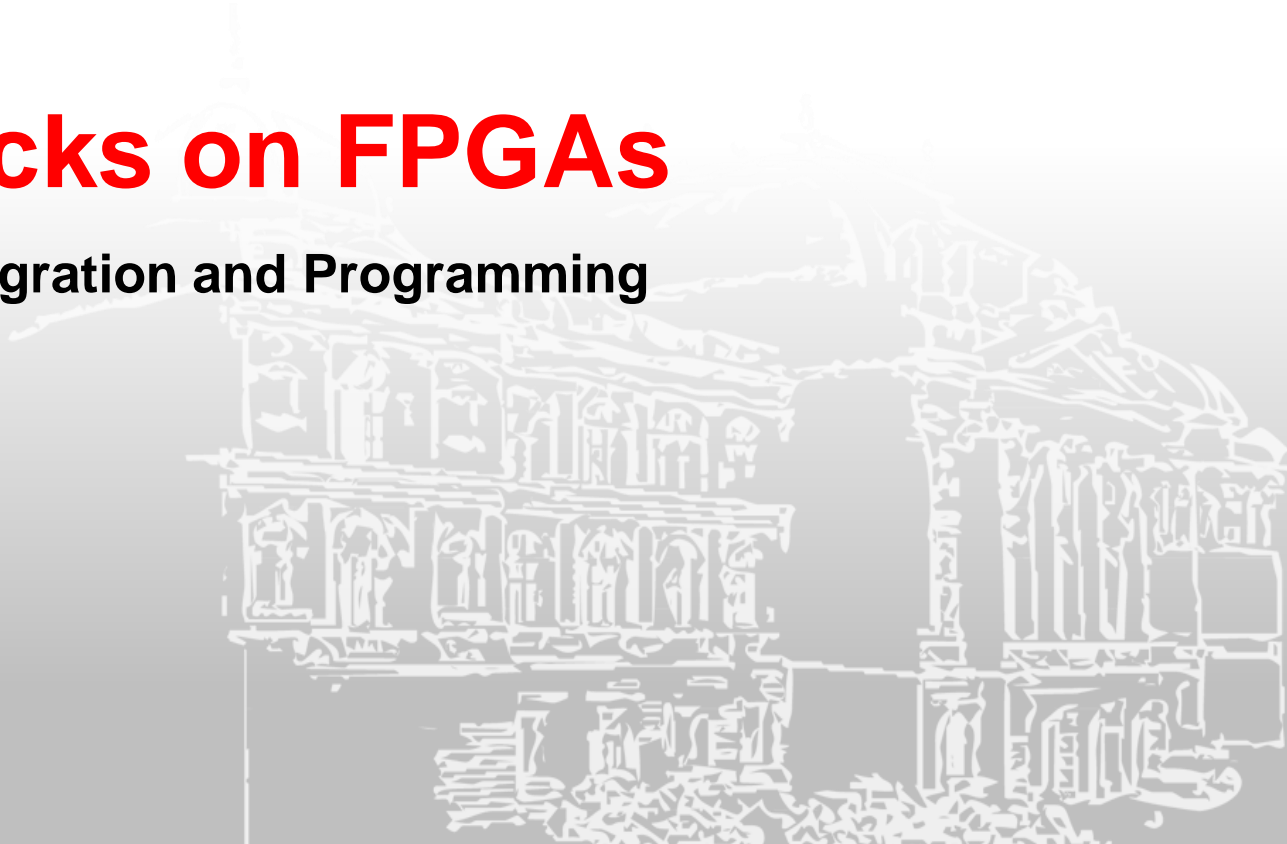


Fault Attacks on FPGAs

Digital System Integration and Programming

Lukas Furtner

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Agenda

- Fault Attacks in General
- Fault Attacks on FPGAs
- Conclusion/Comparison
- References

Fault Attacks in General

Fault Attacks

- Physical attack
 - Attack on hardware's properties [1]
 - Attack model: the attacker has access to the device
- Intentionally change device's operating condition
 - Various attack vectors (power, temperature ...)
- Unintended behavior of the system can happen
 - Bit flips
 - Different timing behavior of hardware

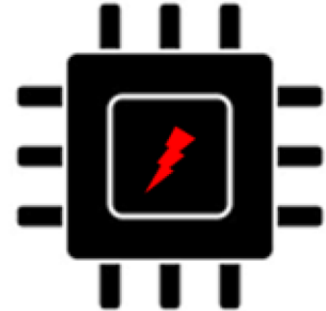


Fig. 1: Abstract fault on Chip

Fault Attacks

- Invasive method
 - Property of destruction
 - Chip modification
 - Chip suffers damage
- Non-invasive method
 - Do not damage the system
 - Not traceable

Fault Attacks

- Main attack vectors [1]
 - Voltage spikes
 - CMOS propagation delay is voltage dependent
 - Lower voltage, higher switching time $T_d \propto \frac{1}{V}$
 - Temperature
 - Higher temperature
 - Lower impedance for CMOS-channels
 - Higher impedance for transmission lines

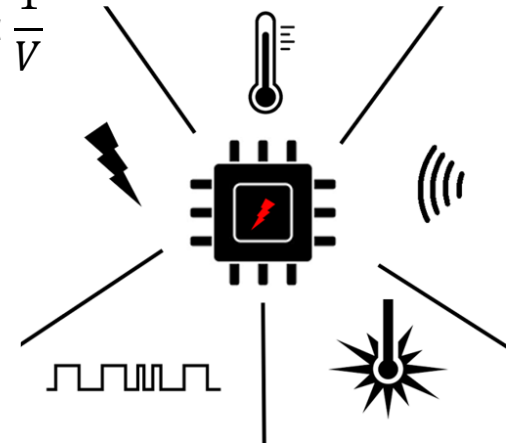


Fig. 2: Types of faults

Fault Attacks

- Main attack vectors [1]
 - Electromagnetic injection
 - Principle of induction
 - Flipping transistors
 - Laser injection
 - Ionization, Heating through Laser [2]
 - Clock glitching
 - Only with external clock sources
 - Create state transition when calculation is not finished

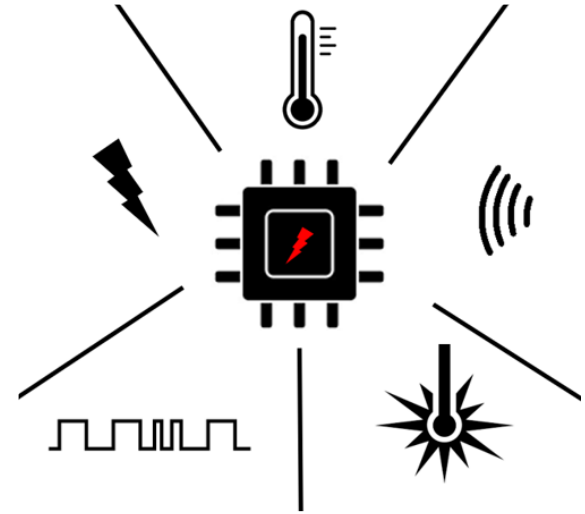


Fig. 3: Types of faults

Fault Attacks

- Effects of successful fault attack [1]
 - System changes behavior
 - Reveals sensitive data
 - Faulty computations
 - Broken systems
 - Wrong AI
 - Key recovery
 - System crashes



Fig. 4: PC on fire [3]

Fault Attacks on FPGAs

Fault Attacks on FPGAs

- FPGA's also use CMOS technology
- Similar attack vectors
- Most attractive attack
 - Voltage-Drop based faults
 - Ring oscillators
- Other existing attacks based on
 - Thermal laser stimulation
 - Seebeck voltage on Drain of MOSFET
 - Clock glitch attack

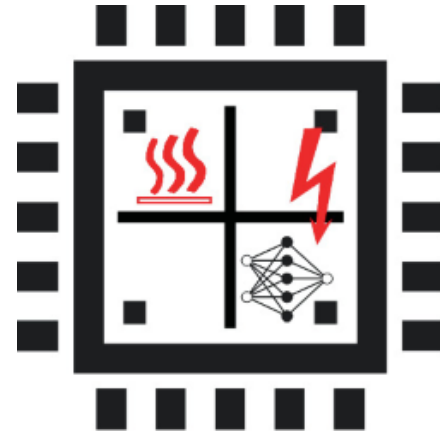


Fig. 5: Fault attack on chip [4]

Performed Fault Attacks on FPGAs

Two different performed attacks:

- First one based on voltage spike
- Second one based on Thermal Laser Stimulation

Remote and Stealthy Fault Attack on Virtualized FPGA

Key Informations

- Voltage based attack
- Executed on multi tenant FPGA
- FPGA-AES attacked
 - Key recovery attack
- Introduced timing faults
 - Between AES rounds
- DFA (Differential Fault Analysis used for key recovery)

Threat Model [5]

- Multi tenant FPGA
 - Attacker and victim on same board

- Logical isolation between

- Shared power supply

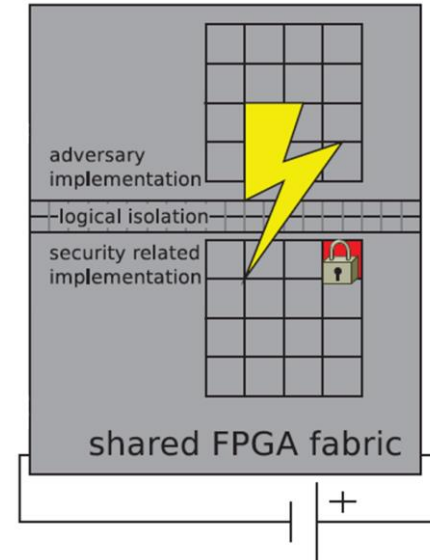


Fig. 6: Threat model 1 [5]

Attack

- Attacker FPGA stream consists of many ring oscillators [5]
- Turn them on at the same time
 - Ring oscillators need a lot of power to be driven
 - If enough ring oscillators
 - Voltage dip on power rail
- Usually 30-50% of the FPGA needed for big enough voltage dip

Attack

- Voltage dip leads to higher transmission [5]
 - AES combinatoric logic does not finish
 - Next state transition introduces faulty state
 - State propagated through scheme
 - Different outputs for correct and faulty value
 - DFA possible

$$T_d \propto \frac{1}{V}$$

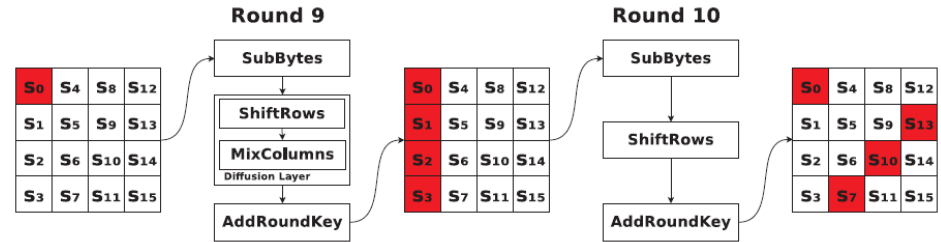


Fig. 7: AES fault propagation [5]

How well does it work

- Very successful attack
- On different FPGAs [6]

- Benchmark IPs also very good for voltage dip attack [6]

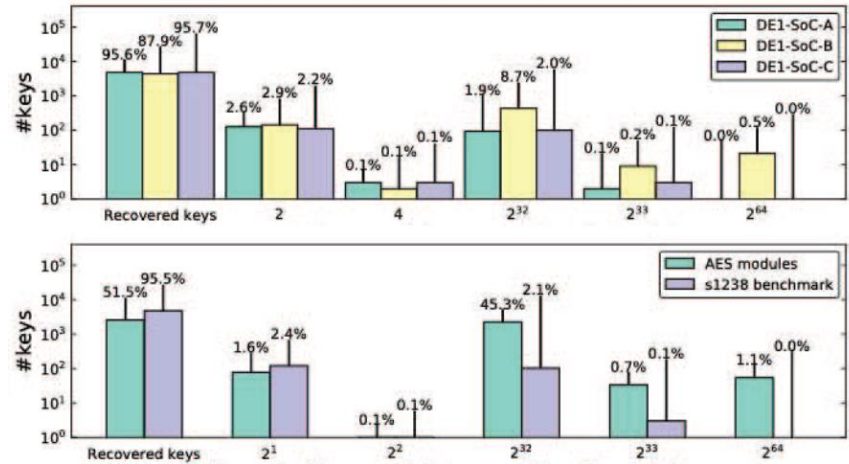


Fig. 8: Success rate of attack (remaining key candidate numbers of 5000 keys [6])

Countermeasures

- Hard to implement [6]
 - Search bitstream for ring oscillators
 - Attack also possible with multiple AES/Benchmark IP-cores
- Better:
 - Search for power intense parts [6]
 - Use separate power rails for them
 - Multi tenant system needs to support that

Key Extraction Using Thermal Laser Stimulation

Key Informations

- Laser Injection based attack
- Executed on physical accessible FPGA
- FPGA-battery-backed SRAM attacked (BBRAM)
 - AES key of bitstream stored in there
 - Used for decrypting bitstream from non-volatile memory during startup
- Introduced thermal heating on BBRAM-MOSFETs drain
 - Generates voltage (seebeck-voltage)
 - Can be measured on supply line

Threat Model [2]

- Physical access to the FPGA
- Attacker owns an FPGA of the same type
- Attacker can have but does not need access to the floorplan of the chip

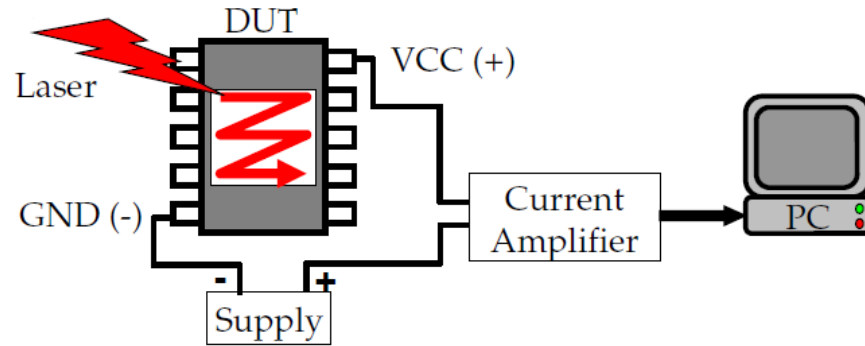


Fig. 9: Threat model 2 [2]

Attack

- Laser beam used to heat drain of MOSFET [7]
 - Temperature gradient
 - Two different metals
 - Diffusion of carriers
 - Seebeck voltage

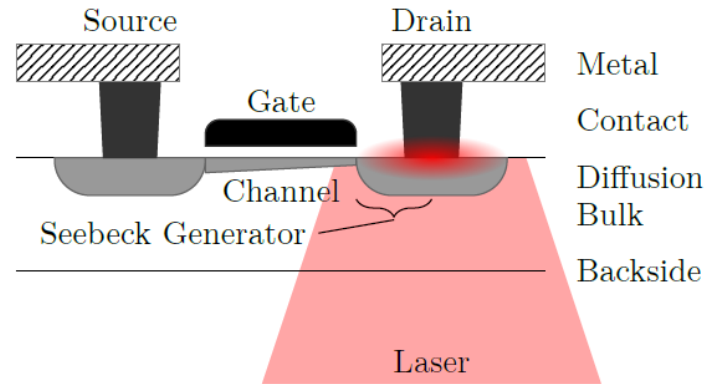


Fig. 10: Introducing Seebeck voltage with Laser [7]

What can be done with that

- SRAM cells
 - Heating MOSFET drain [7]
 - Opposite MOSFET opens a bit (still very high ohmic)
 - Current change on power rail [nA]
 - Only applies for closed connection
 - Active MOSFETs
- Differentiate between 0 and 1 bit

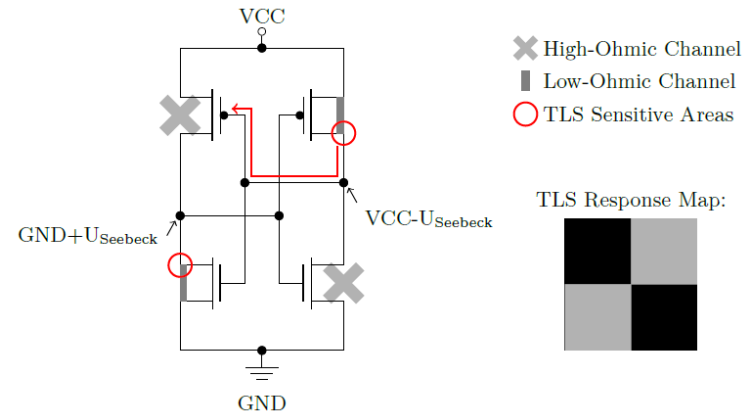


Fig. 11: SRAM bit recovery [7]

FPGAs use BBRAM

- Battery-Backed-SRAM
 - SRAM format can be attacked [8]
 - Battery backed
 - Low noise - better detection of small currents
- 2D-Map of laser stimulation created [8]
- Reference with 0 bits
- Create difference

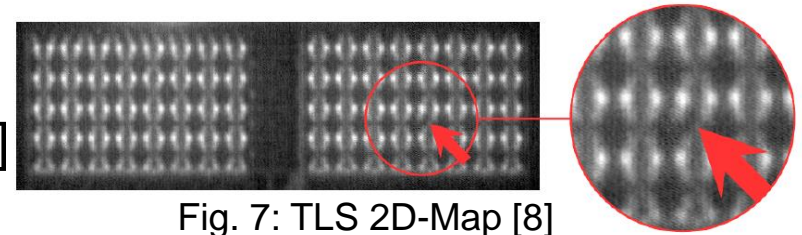
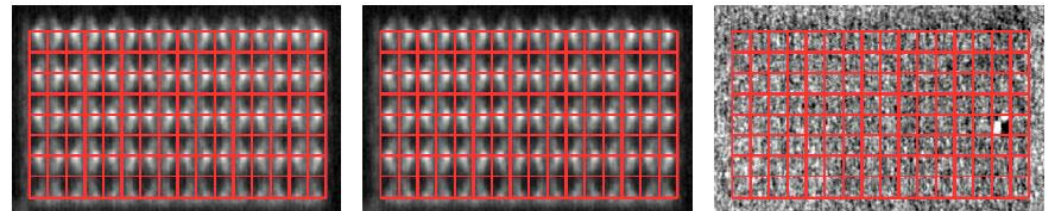


Fig. 7: TLS 2D-Map [8]



Reference

Measurement

Difference

Fig. 12: Difference of TLS 2D-Map [8]

Extendable for Whole Key

- Apply threshold for black and white parts [8]
- Cells with black and white
 - Indicate difference to 0 bit
 - Contain a 1

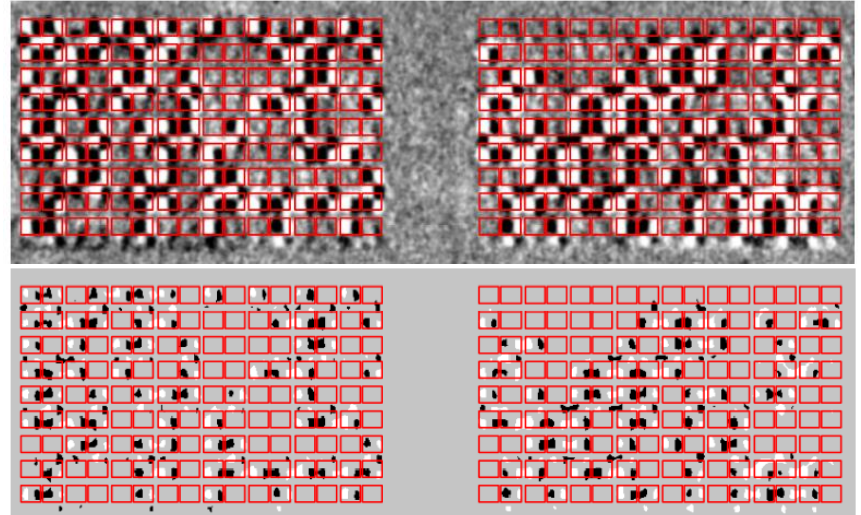


Fig. 13: Whole Key Recovery [8]

Countermeasures

- Noise based countermeasure [8]
 - More measurements reduce SNR
- Light sensors useless
 - To long wavelength
- Temperature sensor would work
 - Battery driven, because attack performed during shut down
- Bit obfuscation by hardware [8]
 - Works, but duplication of circuit still possible
 - Could be revealed at a later point

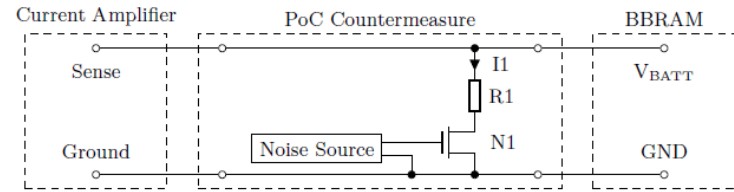


Fig 14: Noise based countermeasure circuit [8]

Comparison of Attacks

First attack

- Attack vector
 - Voltage dips
- Attack on
 - FPGA calculation
- Remote attack
- Relatively easy

Second attack

- Attack vector
 - Thermal Laser Stimulation
- Attack on
 - BBRAM
- Access to device needed
- Expensive equipment

References and Image Sources

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